


<b>Search Notes</b>  	<b>Application/Control No.</b>  10089178	<b>Applicant(s)/Patent Under Reexamination</b>  HIBINO ET AL.
	<b>Examiner</b>  DEVONA E FAULK	<b>Art Unit</b>  2615

SEARCHED			
Class	Subclass	Date	Examiner
381	86	5/31/06	BTP
381	86,302,102-109	4/26/07	DEF
381	86,302,102-109	5/19/08	DEF
455	345,569.2	5/20/08	DEF
381	302,86	12/7/08	DEF

SEARCH NOTES		
Search Notes	Date	Examiner
Assignee/Inventor search	4/26/07	DEF
reviewed applicant's arguments, maintained rejection	10/18/07	DEF
additonal search	5/19/08	DEF
additional search	12/7/08	DEF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/DEVONA E FAULK/ Examiner.Art Unit 2614	
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